

Search Notes

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Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under
Reexamination

MIMURA, IKUO

Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner
340	572.7	10/12/2006	JAT
	572.1	10/12/2006	JAT
359	529	10/12/2006	JAT
	530	10/13/2006	JAT
	531	10/13/2006	JAT
	532	10/13/2006	JAT
	533	10/13/2006	JAT
	536	10/13/2006	JAT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR